

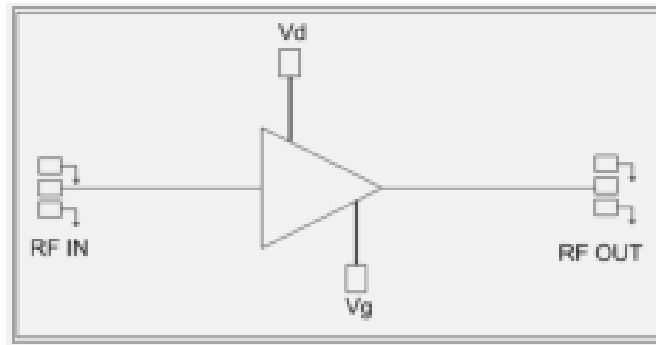
Features

- Frequency: DC-67GHz
- Small Signal Gain: 8dB
- Psat: 17dBm
- Power supply: +7V/110mA
- Input/Output: 50Ω
- Die Size: 2.5 x 1.2 x 0.1 mm

Typical Applications

- Test Instrumentation
- Microwave Radio & VSAT
- Military & Space
- Telecom Infrastructure
- Fiber Optics

Functional Block Diagram

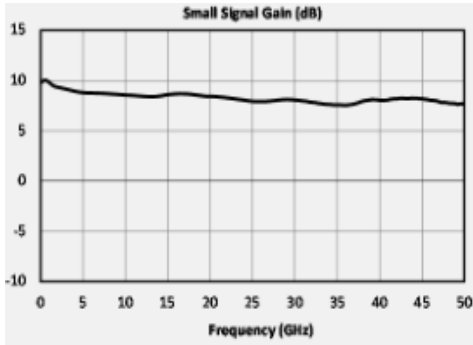


Electrical Specifications

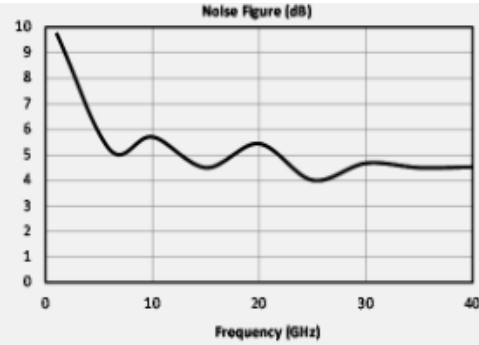
TA = +25°C, Vd = +7V

Parameters	Min.	Typ.	Max.	Units
Frequency	DC-50*			GHz
Small Signal Gain** (Negative Bias)		8		dB
P1dB** (Negative Bias)		13		dBm
Psat** (Negative Bias)		17		dBm
Input Return Loss		15		dB
Output Return Loss		10		dB
Static Current		110		mA
<p>*Limited by test conditions, only DC-50G test data are provided. **Adjust VG (-2V-0V) to obtain device current of 125mA. VG can be suspended and at suspension state, the current is 150mA.</p>				

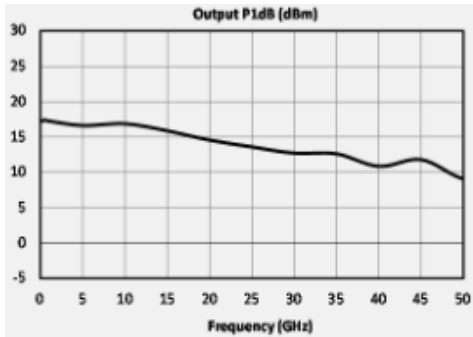
Gain vs. Frequency



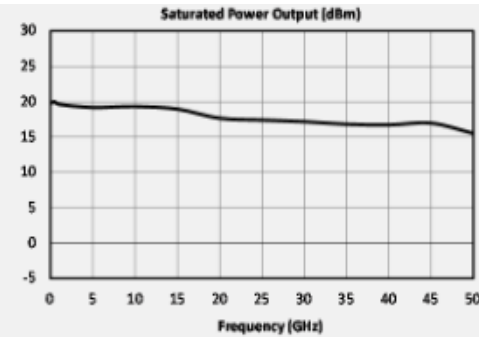
Noise Figure vs. Frequency



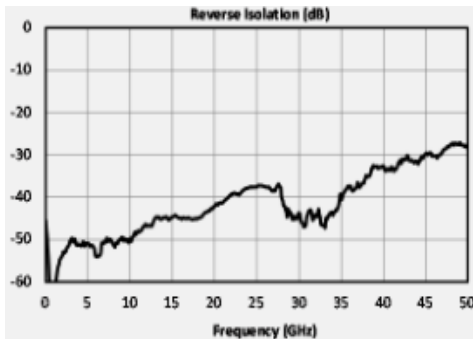
P1dB vs. Frequency



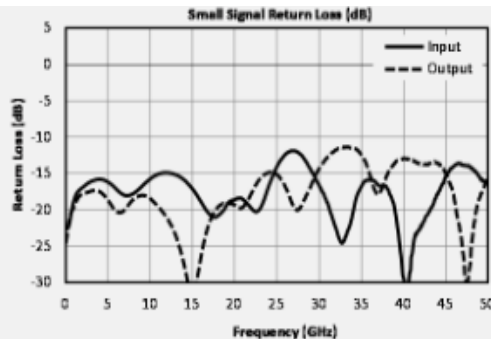
Psat vs. Frequency



Reverse Isolation vs. Frequency

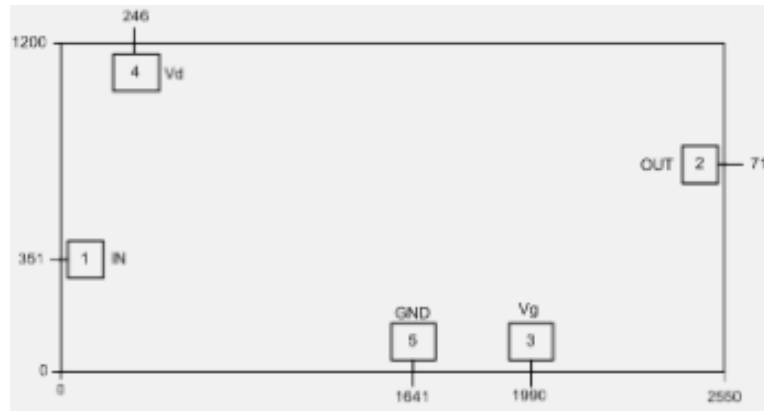


Input/Output Return Loss





Outline Drawing:
All Dimensions in μm

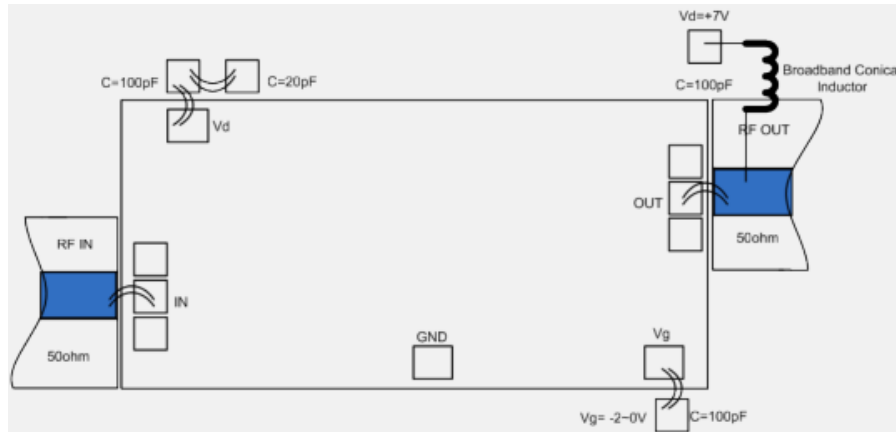


Pad Description

Pad	Function	Description	Equivalent Circuit
1	RF IN	RF signal input terminal; blocking capacitor required.	
2	RF OUT	RF signal output terminal; blocking capacitor required.	
3	Vg	Amplifier gate bias; connected to 100pF bypass capacitor.	
4	Vd	Amplifier drain bias, connected to external 100pF bypass capacitor.	
5	GND	Ground point used for probe test.	
Die bottom	GND	Die bottom must be connected to RF/DC ground.	



Assembly Drawing



Notes:

1. Die thickness: 100um
2. Typical bond pad is 100*100 μm^2
3. Bond pad metalization: Gold
4. Backside metalization: Gold
5. Backside of the die (GND)
6. No connection required for unlabeled bond pads

Maximum Ratings:

1. Maximum drain voltage: +9V
2. Maximum gate bias: -2V
3. Maximum input power: +15dBm
4. Operating temperature: -55°C to +85°C
5. Storage temperature: -65°C to +150°C